

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10710332	BONALLE ET AL.	
	Examiner	Art Unit	Page 1 of 3
Daniel I. Walsh	2876		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,910,521 A	03-1990	Mellon, Donald W.	342/45
*	B	US-6,060,815 A	05-2000	Nysen, Paul A.	310/318
*	C	US-2002/0175805 A9	11-2002	Armstrong et al.	340/10.31
*	D	US-2003/0006901 A1	01-2003	Kim et al.	340/572.5
*	E	US-6,609,656 B1	08-2003	Elledge, Dennis D.	235/382
*	F	US-2006/0033609 A1	02-2006	Bridgelall, Raj	340/010.42
*	G	US-2006/0066444 A1	03-2006	Steeves, Wayne E.	340/010.5
*	H	US-2006/0071756 A1	04-2006	Steeves, Wayne E.	340/010.1
*	I	US-7,059,159 B2	06-2006	Lanigan et al.	70/280
*	J	US-2006/0202835 A1	09-2006	Thibault, Ronald M.	340/573.1
*	K	US-7,102,523 B2	09-2006	Shanks et al.	340/572.7
*	L	US-2007/0008131 A1	01-2007	Doan et al.	340/572.1
*	M	US-2007/0046468 A1	03-2007	Davis, Michael L.	340/572.1

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/710,332	BONALLE ET AL.	
Examiner		Art Unit		Page 2 of 3
Daniel I. Walsh		2876		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,993,068 A	02-1991	Piosenka et al.	713/186
*	B	US-5,259,649 A	11-1993	Shomron, Gur	283/114
*	C	US-5,578,808 A	11-1996	Taylor, Douglas C.	235/380
*	D	US-5,764,789 A	06-1998	Pare et al.	382/115
*	E	US-6,104,311 A	08-2000	Lastinger, Roc A.	340/10.51
*	F	US-6,130,623 A	10-2000	MacLellan et al.	340/5.1
*	G	US-2002/0036237 A1	03-2002	Atherton et al.	235/492
*	H	US-2003/0155416 A1	08-2003	Macklin et al.	235/380
*	I	US-2003/0159044 A1	08-2003	Doyle et al.	713/176
*	J	US-6,636,620 B1	10-2003	Hoshino, Satoshi	382/124
*	K	US-6,732,919 B2	05-2004	Macklin et al.	235/380
*	L	US-6,765,470 B2	07-2004	Shinzaki, Takashi	340/5.52
*	M	US-2007/0057797 A1	03-2007	Waldner et al.	340/572.7

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
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	R					
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NON-PATENT DOCUMENTS

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	U	
	V	
	W	
	X	

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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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		10/710,332	BONALLE ET AL.	
Examiner		Art Unit		Page 3 of 3
Daniel I. Walsh		2876		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,826,243 A	10-1998	Musmanno et al.	705/35
*	B	US-6,265,977 B1	07-2001	Vega et al.	340/572.7
*	C	US-2001/0040507 A1	11-2001	Eckstein et al.	340/572.4
*	D	US-6,940,461 B2	09-2005	Nantz et al.	343/713
*	E	US-7,049,962 B2	05-2006	Atherton et al.	340/572.1
*	F	US-7,132,946 B2	11-2006	Waldner et al.	340/572.1
*	G	US-2007/0075841 A1	04-2007	MALTSEV et al.	340/010.51
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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